

STD7NK30Z, STF7NK30Z STP7NK30Z

N-channel, 300 V, 0.80 Ω, 5 A TO-220, TO-220FP, DPAK Zener-protected SuperMESH™ Power MOSFET

Features

Туре	V _{DSS}	R _{DS(on)} max	I _D	Pw
STF7NK30Z	300 V	< 0.9 Ω	5 A	20 W
STP7NK30Z	300 V	< 0.9 Ω	5 A	50 W
STD7NK30Z	300 V	< 0.9 Ω	5 A	50 W

- 100% avalanche tested
- Extremely high dv/dt capability
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability

Applications

Switching application

Description

The SuperMESH[™] series is obtained through an extreme optimization of ST's well established strip-based PowerMESH[™] layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage Power MOSFETs including revolutionary MDmesh[™] products

Table 1.	Device	summary
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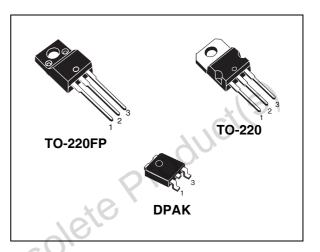
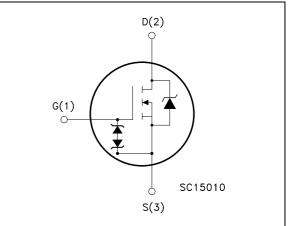


Figure 1. Internal schematic diagram



Order codes	Marking	Package	Packaging
STD7NK30Z	D7NK30Z	DPAK	Tape and reel
STF7NK30Z	F7NK30Z	TO-220FP	Tube
STP7NK30Z	P7NK30Z	TO-220	Tube

March 2009

1 Electrical ratings

Table 2.Absolute maximum ratings

Symbol	Parameter	Valu	Unit	
Symbol	Farameter	TO-220, DPAK	TO-220FP	Unit
V _{DS}	Drain-source voltage ($V_{GS} = 0$)	300)	V
V _{GS}	Gate- source voltage	± 30)	V
I _D	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	5	5 ⁽¹⁾	Α
I _D	Drain current (continuous) at $T_C = 100 \ ^{\circ}C$	3.2	3.2 ⁽¹⁾	A
I _{DM} ⁽²⁾	Drain current (pulsed)	20 20 (1)		A
P _{TOT}	Total dissipation at $T_C = 25 \text{ °C}$	50	20	W
	Derating factor	0.4	0.16	W/°C
V _{ESD(G-S)}	Gate source ESD(HBM-C=100 pF, R=1.5 k\Omega)	2800		V
dv/dt ⁽³⁾	Peak diode recovery voltage slope	4.5		V/ns
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink $(t=1 \text{ s};T_C=25 \text{ °C})$		2500	V
T _j T _{stg}	Operating junction temperature Storage temperature -55 to 150			V

1. Limited only by maximum temperature allowed

2. Pulse width limited by safe operating area

3. $I_{SD} \leq$ 5.7 A, di/dt \leq 200 A/µs, VDD =80% $V_{(BR)DSS.}$

Table 3. Absolute maximum ratings

	Table 5.	Absolute maximum ratings			
Symbol		Parameter	Valu	e	Unit
50 ¹	Gymbol	i arameter	TO-220, DPAK	TO-220FP	Onit
005	Rthj-case	Thermal resistance junction-case Max	2.50	6.25	V
U.	Rthj-amb	Thermal resistance junction-ambient Max	62.5		V
	T1Maximum lead temperature for soldering purpose300			А	

Table 4. Absolute maximum ratings

5	Symbol	Parameter	rameter Value	
	I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_j max)	5	A
	E _{AS}	Single pulse avalanche energy (starting $T_j = 25 \text{ °C}$, $I_D = I_{AR}$, $V_{DD} = 50 \text{ V}$)	130	

2 **Electrical characteristics**

(Tcase =25 °C unless otherwise specified)

Table 5.	Un/on states					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{\rm D}$ =1 mA, $V_{\rm GS}$ = 0	300			V
I _{DSS}	Zero gate voltage	V _{DS} =max rating			1	μA
I _{GSS}	drain current ($V_{GS} = 0$) Gate-body leakage current ($V_{DS} = 0$)	V_{DS} =max rating @125 °C V_{GS} = ± 20 V			50 ±10	μΑ μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 50 \ \mu A$	3	3.75	4.5	V
R _{DS(on)}	Static drain-source on resistance	V_{GS} = 10 V, I _D = 2.5 A		0.80	0.90	Ω
Table 6	Dynamic	Q	0			

Table 5 On/off states

Table 6. Dynamic

	Bynamie					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 2.5 \text{ A}$		2.5		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25 V, f = 1MHz, V _{GS} = 0		380 74 15		pF pF pF
C _{oss eq.} ⁽²⁾	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0$ to 240 V		30		pF
Qg	Total gate charge	$V_{DD} = 240 \text{ V}, \text{ I}_{D} = 7 \text{ A},$		13		nC
Q _{gs}	Gate-source charge	V _{GS} = 10 V		4.5	17	nC
Q _{gd}	Gate-drain charge	Figure 16		7.6		nC
2. Coss on is	ulse duration = 300 µs, duty cyc defined as a constant equivaler from 0 to 80% V _{DSS} .	le 1.5%. It capacitance giving the same cha	arging tim	e as C _{oss}	, when V	DS



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off-delay time Fall time	$V_{DD} = 150 \text{ V}, \text{ I}_{D} = 3.5 \text{ A}, \\ \text{R}_{\text{G}} = 4.7 \ \Omega, \text{ V}_{\text{GS}} = 10 \text{ V} \\ \textbf{Figure 15}$		11 25 20 10		ns ns ns ns
t _{r(Voff)} t _f t _c	Off-voltage rise time Fall time Cross-over time	$\label{eq:VDD} \begin{array}{l} V_{DD} = 240 \; V, \; I_{D} = 7 \; A, \\ R_{G} = 4.7 \; \Omega, \; V_{GS} = 10 \; V \\ \hline \textit{Figure 15} \end{array}$		8.5 8.5 20		ns ns ns

Table 7. Switching times

Table 8. **Source Drain Diode**

						- V
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)	<	210	00	5 20	A A
V _{SD} ⁽²⁾	Forward On voltage	$I_{SD} = 5 \text{ A}, V_{GS} = 0$			1.6	V
t _{rr}	Reverse recovery time	I _{SD} = 7 A, di/dt = 100 A/µs		154		ns
Q _{rr}	Reverse recovery charge	V _{DD} = 40 V, T _j = 150 °C		716		nC
I _{RRM}	Reverse recovery current	Figure 20		9.3		А
1. Pulse wid	th limited by safe operating area					

1. Pulse width limited by safe operating area.

2. Pulsed: Pulse duration = $300 \mu s$, duty cycle 1.5%.

Table 9. **Gate-source Zener diode**

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BV _{GSO} ⁽¹⁾	Gate-source breakdown voltage	lgs=± 1mA (open drain)	30			v

1. The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components

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Thermal impedance for TO-220

Figure 2.

Electrical characteristics (curves) 2.1

Safe operating area for TO-220

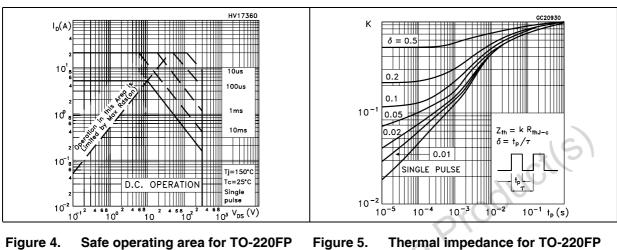


Figure 3.



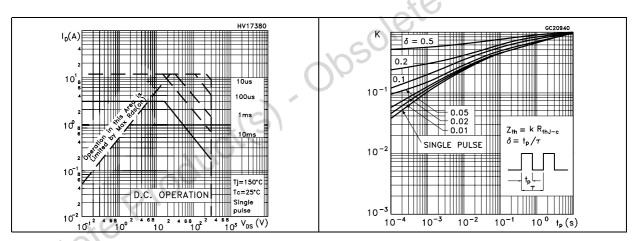


Figure 6. **Output characteristics**



Transfer characteristics

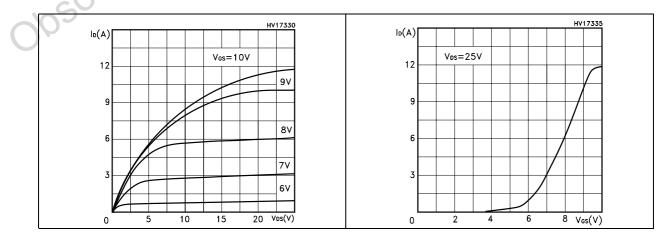


Figure 8. Static drain source on resistance Figure 9. Normaliz



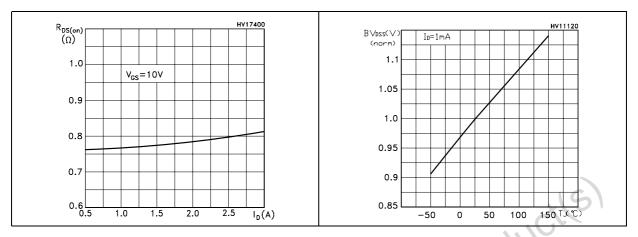


Figure 10. Gate charge vs gate-source voltage Figure 11. Capacitance variations

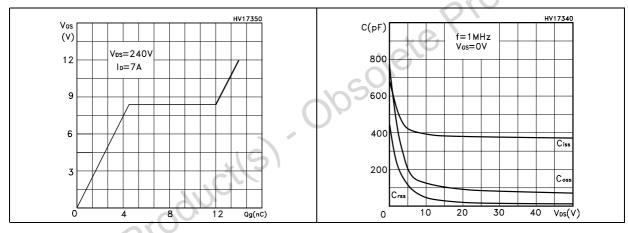


Figure 12. Normalized gate threshold voltage Figure 13. Normalized on resistance vs vs temperature temperature

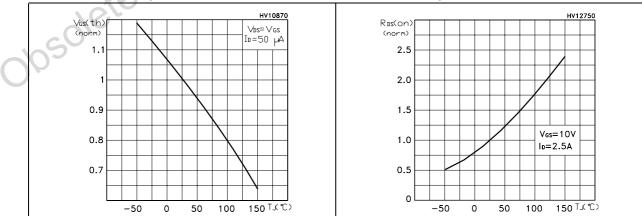


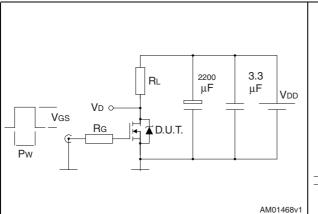
Figure 14. Source-drain diode forward characteristics

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3 Test circuits

Figure 15. Switching times test circuit for resistive load



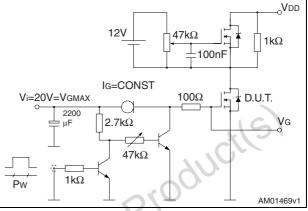


Figure 16. Gate charge test circuit

Figure 17. Test circuit for inductive load switching and diode recovery times



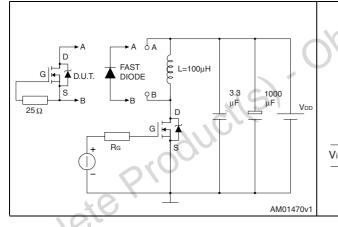


Figure 19. Unclamped inductive waveform

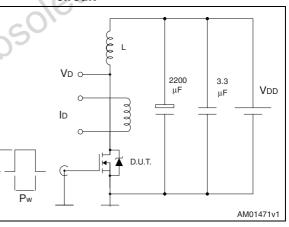
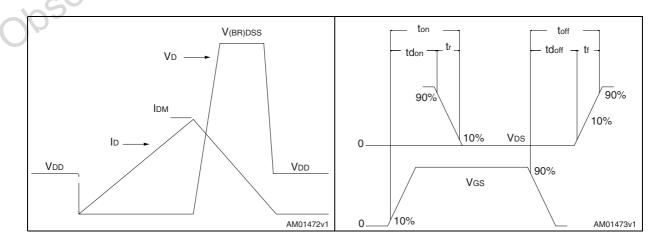


Figure 20. Switching time waveform



4 Package mechanical data

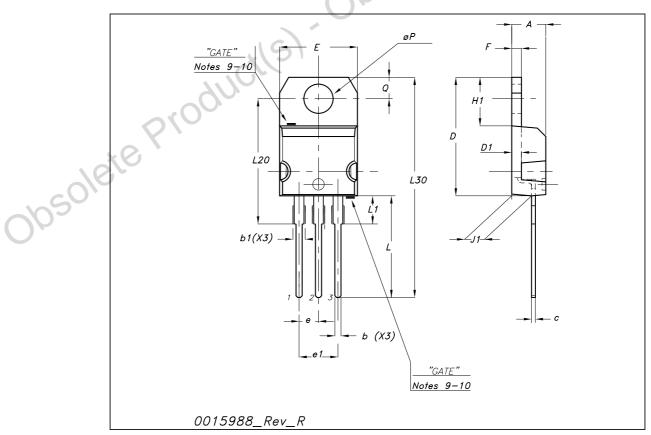
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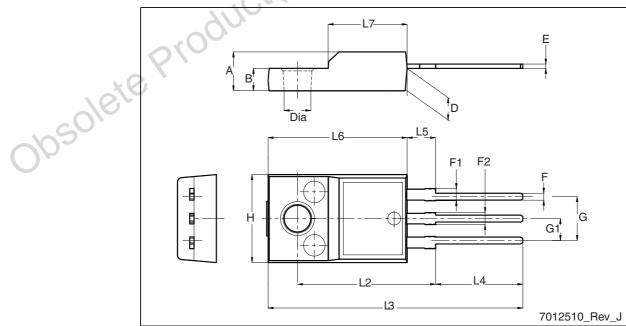
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Dim		mm			inch		
Dilli	Min	Тур	Max	Min	Тур	Max	
А	4.40		4.60	0.173		0.181	
b	0.61		0.88	0.024		0.034	
b1	1.14		1.70	0.044		0.066	
С	0.48		0.70	0.019		0.027	
D	15.25		15.75	0.6		0.62	
D1		1.27			0.050		
E	10		10.40	0.393		0.409	
е	2.40		2.70	0.094		0.106	
e1	4.95		5.15	0.194		0.202	
F	1.23		1.32	0.048		0.051	
H1	6.20		6.60	0.244	NO.	0.256	
J1	2.40		2.72	0.094		0.107	
L	13		14	0.511		0.551	
L1	3.50		3.93 💊	0.137		0.154	
L20		16.40	101		0.645		
L30		28.90	00		1.137		
ØP	3.75		3.85	0.147		0.151	
Q	2.65		2.95	0.104		0.116	

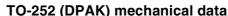


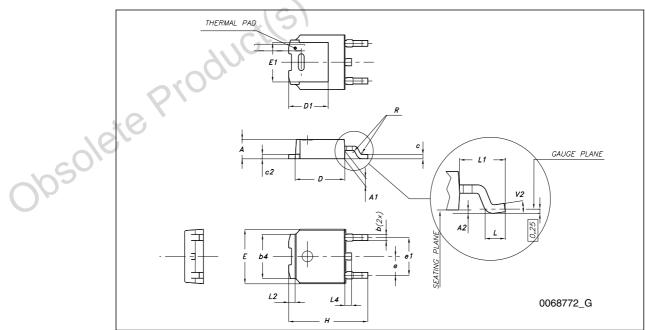


TO-220FP mechanical data			
Disc		mm	
Dim.	Min.	Тур.	Max.
А	4.4		4.6
В	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.5
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6	16,	30.6
L4	9.8	60'	10.6
L5	2.9	703	3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

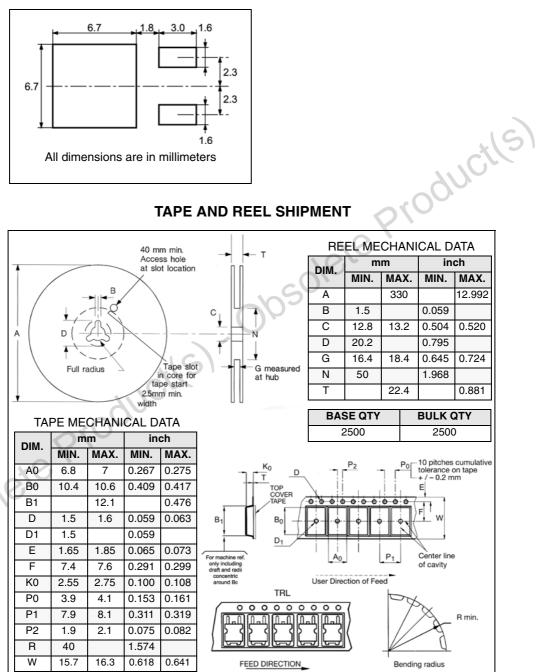


DIM.		mm.	
	min.	typ	max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
с	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1		5.10	G
E	6.40		6.60
E1		4.70	.00
е		2.28	
e1	4.40		4.60
Н	9.35	× 2, `	10.10
L	1		
L1		2.80	
L2		0.80	
L4	0.60	603	1
R		0.20	
V2	0 °		8 ^o





5 Packaging mechanical data



DPAK FOOTPRINT



6 Revision history

Table 10.	Revision	history
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	Date	Revision	Changes
	10-May-2005	1	New stylesheet
	05-Sep-2005	2	Inserted Ecopack indication
	04-Jan-2006	3	Some values changed on table 8.
	22-Mar-2006	4	Inserted DPAK
	05-Mar-2009	5	Section 4: Package mechanical data has been updated
obsole	tepro	ductl	Section 4: Package mechanical data has been updated

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